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## **EUROPEAN PATENT OFFICE**

## **Patent Abstracts of Japan**

**PUBLICATION NUMBER** 

04064223

**PUBLICATION DATE** 

28-02-92

**APPLICATION DATE** 

04-07-90

APPLICATION NUMBER

02179012

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INT.CL.

: H01L 21/285 C23C 16/14

TITLE

MANUFACTURE OF SEMICONDUCTOR DEVICE

ABSTRACT: PURPOSE: To reduce contact resistance by supplying both a reaction gas and a carrier gas, chemically vapor-growing a second W layer on the surface of a first W layer, stopping the supply of the reaction gas so as to externally diffuse fluorine and continuing the feed of the carrier gas.

> CONSTITUTION: A reaction gas mixed with a carrier gas, WF<sub>6</sub> and SiH<sub>4</sub>, in the growth process of W are fed intermittently. F contained in a first W layer grown at a first supply timing before a first stopping timing is diffused externally and washed away by the carrier gas not stopped at the first stopping timing when WF<sub>6</sub> and SiH<sub>4</sub> are not supplied. A novel second W layer is laminated and grown on the first W layer, from which F is removed, at a second supply timing, and F contained in the anew grown second W layer is diffused externally and washed away by the carrier gas and taken off. The process of growth and F removal is repeated, thus forming a buried W layer having specified thickness.

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